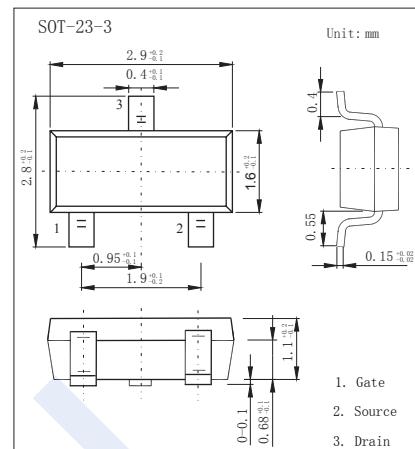
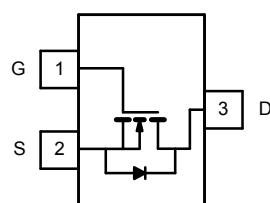


## N-Channel Enhancement MOSFET

## SI2304DS (K12304DS)

## ■ Features

- $V_{DS} (V) = 30V$
- $R_{DS(ON)} < 117m\Omega$  ( $V_{GS} = 10V$ )
- $R_{DS(ON)} < 190m\Omega$  ( $V_{GS} = 4.5V$ )

■ Absolute Maximum Ratings  $T_a = 25^\circ C$ 

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	
Continuous Drain Current ( $T_j = 150^\circ C$ ) *1	$I_D$	2.5	A
		2.0	
Pulsed Drain Current *2	$I_{DM}$	10	
Power Dissipation	$P_D$	1.25	W
		0.8	
Thermal Resistance.Junction- to-Ambient *1	$R_{thJA}$	100	°C/W
Thermal Resistance.Junction- to-Ambient *3		166	
Junction Temperature	$T_J$	150	°C
Storage Temperature Range	$T_{stg}$	-55 to 150	

\*1 Surface Mounted on FR4 Board,  $t \leqslant 5$  sec.

\*2 Pulse width limited by maximum junction temperature.

\*3 Surface Mounted on FR4 Board.

## N-Channel Enhancement MOSFET

## SI2304DS (KI2304DS)

■ Electrical Characteristics  $T_a = 25^\circ\text{C}$

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{DSS}$	$I_D=250 \mu\text{A}, V_{GS}=0\text{V}$	30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$			0.5	$\mu\text{A}$
		$V_{DS}=30\text{V}, V_{GS}=0\text{V}, T_a=55^\circ\text{C}$			10	
Gate-Body Leakage Current	$I_{GSS}$	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS}=V_{GS}, I_D=250 \mu\text{A}$	1.5		3	V
On-State Drain Current *1	$I_{D(on)}$	$V_{DS} \geq 4.5\text{ V}, V_{GS} = 10\text{ V}$	6			A
		$V_{DS} \geq 4.5\text{ V}, V_{GS} = 4.5\text{ V}$	4			
Static Drain-Source On-Resistance *1	$R_{DS(on)}$	$V_{GS}=10\text{V}, I_D=2.5\text{A}$		92	117	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=2.0\text{A}$		142	190	
Forward Transconductance *1	$g_{FS}$	$V_{DS}=4.5\text{V}, I_D=2.5\text{A}$		4.6		S
Input Capacitance	$C_{iss}$	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		240		pF
Output Capacitance	$C_{oss}$			110		
Reverse Transfer Capacitance	$C_{rss}$			17		
Total Gate Charge	$Q_g$	$V_{DS}=15\text{V}, V_{GS}=5\text{V}, I_D=2.5\text{A}$		2.4	4	nC
Gate-Source Charge	$Q_{gt}$	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=2.5\text{A}$		4.5	10	
Gate Source Charge	$Q_{gs}$			0.8		
Gate Drain Charge	$Q_{gd}$			1.0		
Turn-On DelayTime	$t_{d(on)}$	$I_D=1\text{A}, V_{DS}=15\text{V}, R_{GEN}=6\Omega$		8	20	ns
Turn-On Rise Time	$t_r$			12	30	
Turn-Off DelayTime	$t_{d(off)}$			17	35	
Turn-Off Fall Time	$t_f$			8	20	
Maximum Body-Diode Continuous Current	$I_S$				1.25	A
Diode Forward Voltage	$V_{SD}$	$I_S=1.25\text{A}, V_{GS}=0\text{V}$		0.77	1.2	V

\*1 Pulse test: PW  $\leq 300\text{us}$  duty cycle  $\leq 2\%$ .

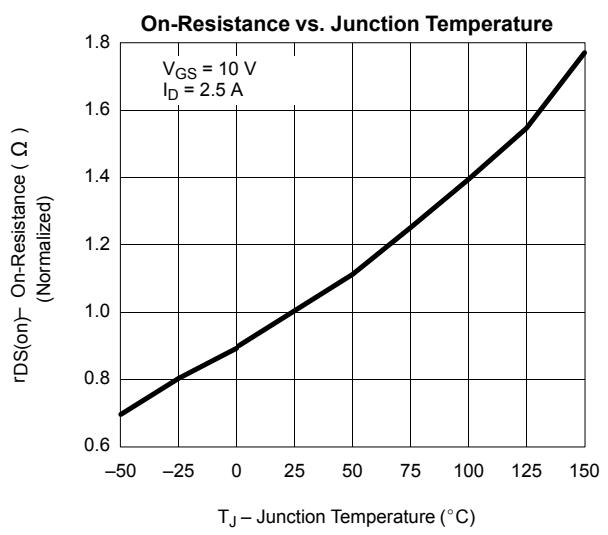
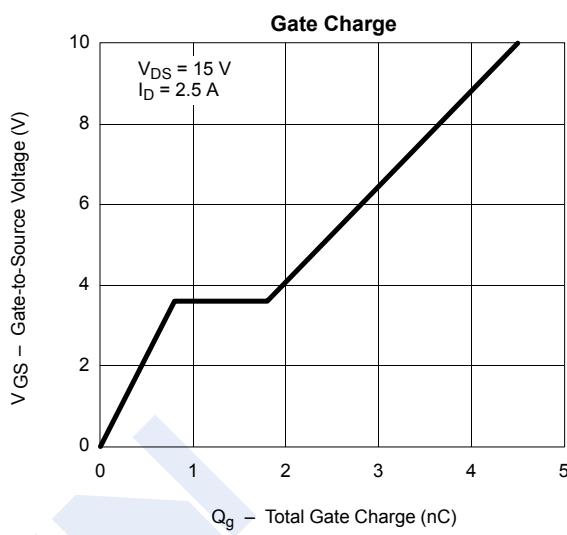
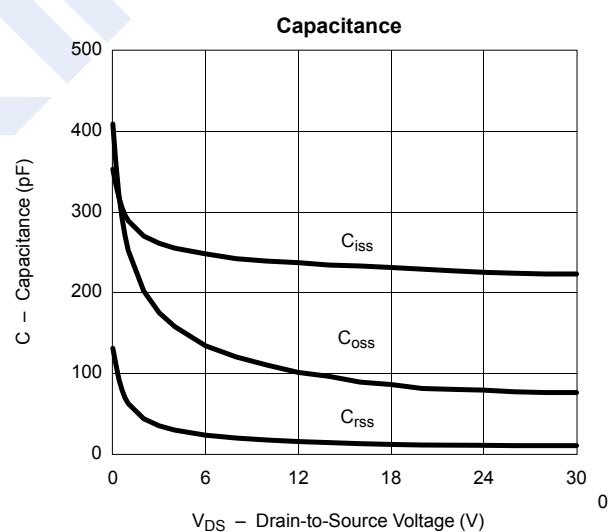
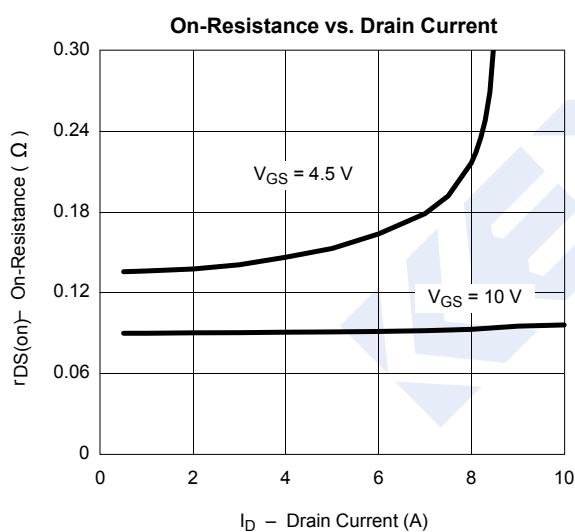
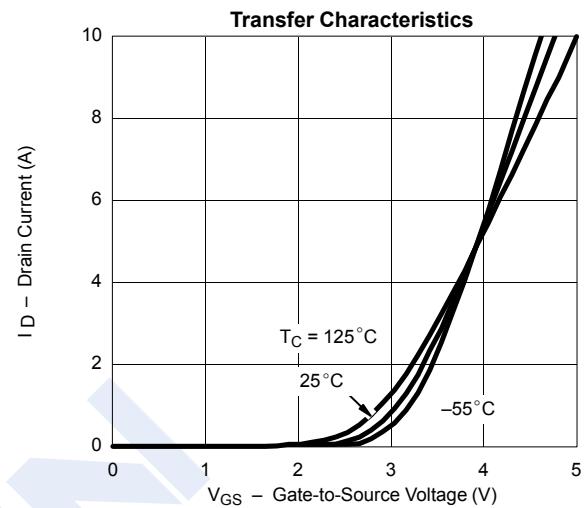
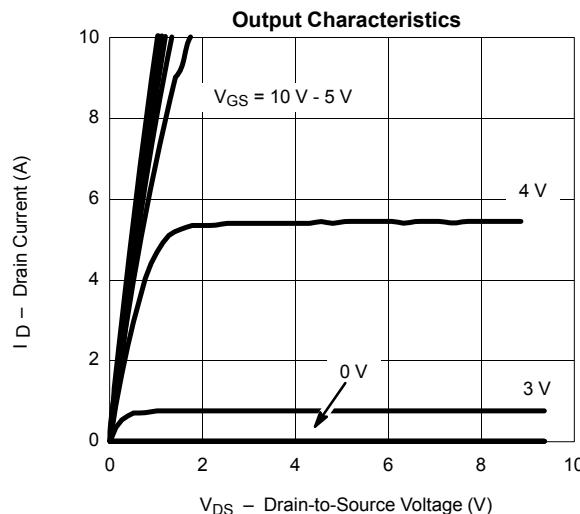
## ■ Marking

Marking	A4*
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## N-Channel Enhancement MOSFET

### SI2304DS (K12304DS)

#### ■ Typical Characteristics



## N-Channel Enhancement MOSFET

SI2304DS (K12304DS)

## ■ Typical Characteristics

